			m
	Application No.	Applicant(s)	70"
Notice of Allowability	10/759,335 Examiner	NALBANDIAN, VA	MAKN _
	Shih-Chao Chen	2821	
The MAILING DATE of this communication appea All claims being allowable, PROSECUTION ON THE MERITS IS (of herewith (or previously mailed), a Notice of Allowance (PTOL-85) of NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIG of the Office or upon petition by the applicant. See 37 CFR 1.313 a	OR REMAINS) CLOSED in r other appropriate commu HTS. This application is s	n this application. If not incluunication will be mailed in du	ded e course. THIS
1. \boxtimes This communication is responsive to <u>the application filed on</u>	<i>Jan.</i> 16, 2004.		
2. A The allowed claim(s) is/are <u>1-60</u> .			
3. \boxtimes The drawings filed on <u>16 January 2004</u> are accepted by the	Examiner.		
 4. Acknowledgment is made of a claim for foreign priority und a) All b) Some* c) None of the: 1. Certified copies of the priority documents have to 2. Certified copies of the priority documents have to 3. Copies of the certified copies of the priority documents have to 3. Copies of the certified copies of the priority documents have to 1. Certified copies not received: Applicant has THREE MONTHS FROM THE "MAILING DATE" of noted below. Failure to timely comply will result in ABANDONMETHIS THREE-MONTH PERIOD IS NOT EXTENDABLE. 5. A SUBSTITUTE OATH OR DECLARATION must be submitted in INFORMAL PATENT APPLICATION (PTO-152) which gives are comply including changes required by the Notice of Draftsperson 1) hereto or 2) to Paper No./Mail Date (b) including changes required by the attached Examiner's repair No./Mail Date Identifying Indicia such as the application number (see 37 CFR 1.8 each sheet. Replacement sheet(s) should be labeled as such in the paper No./Mail Date 7. DEPOSIT OF and/or INFORMATION about the deposition attached Examiner's comment regarding REQUIREMENT Foreign and paper No./Mail page attached Examiner's comment regarding REQUIREMENT Foreign attached Examiner's comment regarding Requirement attached Examiner attached Examiner at the	peen received. Deen received in Application aments have been received in this communication to file NT of this application. The ed. Note the attached EXA reason(s) why the oath or the submitted. The patent Drawing Review Amendment / Comment or the header according to 37 CF to f BIOLOGICAL MATERIAL	In No If in this national stage application this national stage application are ply complying with the read and the complying with the read are ply complying with the read are ply complying with the read are ply complying with the read are placed as a reply complying with the read are placed are pla	equirements NOTICE OF
Attachment(s) 1. ☑ Notice of References Cited (PTO-892) 2. ☐ Notice of Draftperson's Patent Drawing Review (PTO-948) 3. ☐ Information Disclosure Statements (PTO-1449 or PTO/SB/08 Paper No./Mail Date 4. ☐ Examiner's Comment Regarding Requirement for Deposit of Biological Material	6. ☐ Interview So Paper No./), 7. ⊠ Examiner's	formal Patent Application (Pummary (PTO-413), Mail Date Amendment/Comment Statement of Reasons for A	llowance two chem

Art Unit: 2821

DETAILED ACTION

EXAMINER'S AMENDMENT

1. An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.

The application has been amended as follows:

In claim 3, line 2, "said radiating arches" is changed to --said radiating arch--.

In claim 3, line 3, "said radiating arches" is changed to --said radiating arch--.

Allowable Subject Matter

- 2. Claims 1-60 are allowed.
- 3. The following is an examiner's statement of reasons for allowance:

The primary reason for the allowance of claims 1-16 and 32-46 is the inclusion of the limitations of a center probe of a coaxial connector projects upwardly through the ground plane, the dielectric substrate and an opening in a first one of the segments, the opening having an opening diameter greater than a probe diameter of the center probe prevents an electrical contact between the center probe and the first segment; and the radiating arch having an inner edge, an outer edge, a first straight end, a second straight end and a path length difference between the plurality of gaps, the inner edge being shorter than said outer edge. It is these limitations found in each of the claims, as they are claimed in the combination, that has not been found, taught or suggested by the prior art of record which makes these claims allowable over the prior art.

Application/Control Number: 10/759,335

Art Unit: 2821

The primary reason for the allowance of claims 17-31 is the inclusion of the limitations of a power supply network disposed beneath the ground plane feeds RF power to a plurality of center probes projecting upwardly through the ground plane, the dielectric substrate and the openings, the openings each having an opening diameter greater than a probe diameter of the center probe prevents an electrical contact between the center probe and the first segments; and each of the plurality of radiating arches having an inner edge, an outer edge, a first straight end, a second straight end and a path length difference between the plurality of gaps, the inner edges being shorter than the outer edges. It is these limitations found in each of the claims, as they are claimed in the combination, that has not been found, taught or suggested by the prior art of record which makes these claims allowable over the prior art.

The primary reason for the allowance of claims 47-60 is the inclusion of the limitations of the steps of forming a radiating arch from the segments, the radiating arch having an inner edge, an outer edge, a first straight end, a second straight end and a path length difference between the plurality of narrow gaps in the radiating arch, the inner edge being shorter than the outer edge; and projecting a center probe of a coaxial connector upwardly through the ground plane, the dielectric substrate and an opening in a first one of the segments, the opening having an opening diameter greater than a probe diameter of the center probe prevents an electrical contact between the center probe and the first segment. It is these limitations found in each of the claims, as they are claimed in the combination, that has not been found, taught or suggested by the prior art of record which makes these claims allowable over the prior art.

Application/Control Number: 10/759,335 Page 4

Art Unit: 2821

Noujeim (U.S. Patent No. 6,839,030) teaches the leaky-wave microstrip antenna includes a grounded element, a dielectric member coupled to the grounded element and a top conducting strip coupled to the dielectric member, the conducting strip including a first and second non-radiating conducting strip and a plurality of radiating cells. However, Noujeim does not disclose or suggest a center probe of a coaxial connector projects upwardly through the ground plane, the dielectric substrate and an opening in a first one of the segments, the opening having an opening diameter greater than a probe diameter of the center probe prevents an electrical contact between the center probe and the first segment; and the radiating arch having an inner edge, an outer edge, a first straight end, a second straight end and a path length difference between the plurality of gaps, the inner edge being shorter than said outer edge.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Correspondence

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Shih-Chao Chen whose telephone number is (571) 272-1819. The examiner can normally be reached on Monday-Friday from 7 AM to 4:30 PM, First Fri. off.

Art Unit: 2821

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Don Wong can be reached on (571) 272-1834. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Shih-Chao Chen Primary Examiner Art Unit 2821

Shik-lao chen

SHIH-CHAO CHEN PRIMARY EXAMINER

SXC May 31, 2005